

NanoKnight: the knight of dimensional nanometrology

An award from the NanoScale committee for outstanding achievements in dimensional nanometrology

Dimensional nanometrology is the science of measurement of the dimensions and tolerances of dimensions that are in the nanometre range. For many years metrologists, particularly those at national metrology institutes have sought to address the challenges of nanometrology. The NanoScale committee has decided that the contributions of exceptional dimensional nanometrologists should be recognized with the award of the title

Nano Knight

In addition it is hoped that the award will help promote dimensional nanometrology to the international community.

Criteria for selection

The recipient of the prize should have an excellent track record of achievements in the field of dimensional nanometrology. This should include scientific publications of their own work, leadership, mentoring of younger scientists and championing of dimensional nanometrology within the international scientific community.

Frequency of Award

The committee will consider candidates every two years and if a suitable candidate is identified the prize will be awarded. Presentations of the award will normally coincide with the NanoScale conference.

Nomination procedure

The prize will be advertised through the NanoScale web site.

Nominations should be made to the chair of the NanoScale committee Dr Ludger Koenders (Ludger.Koenders@ptb.de) by the date given on the NanoScale web site (www.nanoscale.de) and should give reasons for the candidate's nomination. Self-nominations will not be considered.

The winner will be chosen by the NanoScale committee who will also receive advice from experts in the field of dimensional nanometrology outside of Europe.

The 1st NanoKnight is Günter Wilkening!

Presentation ceremony

The award for the 2008 Nano Metrology Knight has been presented at the NanoScale 2008 conference in Torino on September 22nd.

Günter Wilkening received the award for his outstanding work on the field of nanometrology.